Ultramicroscopy 24 (1988) 455–456
North-Holland, Amsterdam

AUTHOR INDEX TO VOLUME 24

Alani, R., see Lundquist 24 (1988) 27
Allan, G.L., see Legge 24 (1988) 283
Andrews, S.B., see Fiori 24 (1988) 237
Artal, P., see Soria 24 (1988) 19
Ast, D.G., see Renteln 24 (1988) 37

Barth, J.E., Realistic comparison of gun lens designs 24 (1988) 1
Bescos, J., see Soria 24 (1988) 19
Bond, M., see LeFurgey 24 (1988) 185
Buonaquisti, A.D. and P.E. Russell, Scanning electron beam submicron analytical techniques 24 (1988) 87
Burns, M.S., Biological microanalysis by secondary ion mass spectrometry: status and prospects 24 (1988) 269

Cantino, M., see Johnson 24 (1988) 221
Chabala, J.M., see Levi-Setti 24 (1988) 97
Cherns, D., C.J. Kiely and A.R. Preston, Electron diffraction studies of strain in epitaxial bicrystals and multilayers 24 (1988) 355
Cowley, J.M., see Fan 24 (1988) 49
Crowther, R.A., see Luther 24 (1988) 7

Downing, K.H., Observations of restricted beam-induced specimen motion with small-spot illumination 24 (1988) 387

Eades, J.A., Guest Editorial 24 (1988) v
Eades, J.A., Microdiffraction's contribution to microcharacterization 24 (1988) 143

Fan, G.Y. and J.M. Cowley, Assessing the information content of HREM images 24 (1988) 49
Fiori, C.E., R.D. Leapman, C.R. Swyt and S.B. Andrews, Quantitative X-ray mapping of biological cryosections 24 (1988) 237
Fromm, I., see Reimer 24 (1988) 339

Goncharov, A.B., see Vainshtein 24 (1988) 61
Gordon, B.M., see Jones 24 (1988) 313
Griffith, O.H. and G.F. Rempfer, Photoelectron imaging and photoelectron labeling 24 (1988) 299
Gronsky, R., Spectroscopic information from high resolution images 24 (1988) 155

Hall, T.A., Capibilities and limitations of probe methods for the microanalysis of chemical elements in biology: a brief introduction 24 (1988) 181
Hanson, A.L., see Jones 24 (1988) 313
Heinemann, K., see Soria 24 (1988) 19
Hren, J.J. and P. Ingram, Foreword to Frontiers of Submicron Spectroscopy and Biological Microanalysis 24 (1988) 83
Hren, J.J. and G. Shedd, Field electron emission, the atom probe and scanning tunneling spectroscopy 24 (1988) 169

Ingram, P., see Hren 24 (1988) 83
Ingram, P., see LeFurgey 24 (1988) 185
Izutsu, K., see Johnson 24 (1988) 221

Johnson, D., K. Izutsu, M. Cantino and J. Wong, High spatial resolution spectroscopy in the elemental microanalysis and imaging of biological systems 24 (1988) 221
Jones, K.W., B.M. Gordon, A.L. Hanson, W.M. Kwiatek and J.G. Pounds, X-ray fluorescence with synchrotron radiation 24 (1988) 313

Kiely, C.J., see Cherns 24 (1988) 355
King, M.A., see Vincent 24 (1988) 409
Kirby, B.J., see Legge 24 (1988) 283
Krishnan, K.M., Atomic site and species determinations using channeling and related effects in analytical electron microscopy 24 (1988) 125
Kwiatek, W.M., see Jones 24 (1988) 313

Lawrence, M.C., see Luther 24 (1988) 7
Leapman, R.D., see Fiori 24 (1988) 237
Leapman, R.D. and R.L. Ornberg, Quantitative electron energy loss spectroscopy in biology 24 (1988) 251
LeFurgey, A., M. Bond and P. Ingram, Frontiers in electron probe microanalysis: application to cell physiology 24 (1988) 185
Legge, G.J.F., P.M. O'Brien, B.J. Kirby and G.L. Allan, Proton microscopy and microanalysis – biological applications 24 (1988) 283
Levi-Setti, R., J.M. Chabala and Y.L. Wang, Aspects of high resolution imaging with a scanning ion microprobe 24 (1988) 97
Lundquist, T.R., R. Alani and P.R. Swann, Reducing focused ion beam charging effects on insulators by heating; a practical method for TEM specimen preparation of nonconductors 24 (1988) 27

Luther, P.K., M.C. Lawrence and R.A. Crowther, A method for monitoring the collapse of plastic sections as a function of electron dose 24 (1988) 7

Moodie, A.F. and H.J. Whitfield, Structure and microstructure in $Ba_2YCu_3O_{7-x}$ 24 (1988) 329

O'Brien, P.M., see Legge 24 (1988) 283
Ornberg, R.L., see Leapman 24 (1988) 251

Pounds, J.G., see Jones 24 (1988) 313
Preston, A.R., see Cherns 24 (1988) 355
Preston, A.R., see Vincent 24 (1988) 409
Pruymboom, A., see Zandbergen 24 (1988) 45

Reimer, L., I. Fromm and R. Rennekamp, Operation modes of electron spectroscopic imaging and electron energy-loss spectroscopy in a transmission electron microscope 24 (1988) 339
Rempfer, G.F., see Griffith 24 (1988) 299
Rennekamp, R., see Reimer 24 (1988) 339
Renteln, P. and D.G. Ast, Lower limit of detectability at high spatial resolution of As implanted into Si using the JEOL 200CX in the STEM–EDX mode 24 (1988) 37
Rüdenauer, F.G. and W. Steiger, Sputter redeposition as a limit to spatially three-dimensional SIMS microanalysis 24 (1988) 115
Russell, P.E., see Buonaquisti 24 (1988) 87
Ryskin, A.J., see Vainshtein 24 (1988) 61

Shedd, G., see Hren 24 (1988) 169
Soria, F., P. Artal, J. Bescos and K. Heinemann, Digital image processing of nanometer-size metal particles on amorphous substrates 24 (1988) 19
Steiger, W., see Rüdenauer 24 (1988) 115
Swann, P.R., see Lundquist 24 (1988) 27
Swyt, C.R., see Fiori 24 (1988) 237

Trebbia, P., Unbiased method for signal estimation in electron energy loss spectroscopy, concentration measurements and detection limits in quantitative microanalysis: methods and programs 24 (1988) 399

Vagin, A.A., see Vainshtein 24 (1988) 61
Vainshtein, B.K., A.B. Goncharov, A.J. Ryskin and A.A. Vagin, Concerning "Angular reconstitution: a posteriori assignment of projection directions for 3D reconstruction" 24 (1988) 61
Van Heel, M., Addendum to "Angular reconstitution: a posteriori assignment of projection directions for 3D reconstruction" 24 (1988) 62
Van Tendeloo, G., see Zandbergen 24 (1988) 45
Vincent, R., A.R. Preston and M.A. King, Measurement of strain in silver halide particles by convergent beam electron diffraction 24 (1988) 409

Wang, Y.L., see Levi-Setti 24 (1988) 97
Wang, Z.L., Dynamical investigations of electron channelling processes in a stepped crystal surface in reflection electron microscopy 24 (1988) 371
Whitfield, H.J., see Moodie 24 (1988) 329
Woldringh, C.L., Editor, Abstracts of papers presented at the Annual Conference of the Netherlands Society of Electron Microscopy, December 1987 24 (1988) 421
Wong, J., see Johnson 24 (1988) 221

Zandbergen, H.W., A. Pruymboom and G. Van Tendeloo, Highly temperature-stable Si_3N_4 perforated grids 24 (1988) 45

Ultramicroscopy 24 (1988) 457–459
North-Holland, Amsterdam

SUBJECT INDEX TO VOLUME 24

Analytical microscopy
Lower limit of detectability at high spatial resolution of As implanted into Si using the JEOL 200CX in the STEM–EDX mode, *Renteln and Ast* 24 (1988) 37
Scanning electron beam submicron analytical techniques, *Buonaquisti and Russell* 24 (1988) 87
Aspects of high resolution imaging with a scanning ion microscope, *Levi-Setti, Chabala and Wang* 24 (1988) 97
Sputter redeposition as a limit to spatially three-dimensional SIMS microanalysis, *Rüdenauer and Steiger* 24 (1988) 115
Atomic site and species determinations using channeling and related effects in analytical electron microscopy, *Krishnan* 24 (1988) 125
Microdiffraction's contribution to microcharacterization, *Eades* 24 (1988) 143
Field electron emission, the atom probe and scanning tunneling spectroscopy, *Hren and Shedd* 24 (1988) 169
Capabilities and limitations of probe methods for the microanalysis of chemical elements in biology: a brief introduction, *Hall* 24 (1988) 181
Frontiers in electron probe microanalysis: application to cell physiology, *LeFurgey, Bond and Ingram* 24 (1988) 185
High spatial resolution spectroscopy in the elemental microanalysis and imaging of biological systems, *Johnson, Izutsu, Cantino and Wong* 24 (1988) 221
Quantitative X-ray mapping of biological cryosections, *Fiori, Leapman, Swyt and Andrews* 24 (1988) 237
Quantitative electron energy loss spectroscopy in biology, *Leapman and Ornberg* 24 (1988) 251
Biological microanalysis by secondary ion mass spectrometry: status and prospects, *Burns* 24 (1988) 269
Proton microscopy and microanalysis – biological applications, *Legge, O'Brien, Kirby and Allan* 24 (1988) 283
Photoelectron imaging and photoelectron labeling, *Griffith and Rempfer* 24 (1988) 299
X-ray fluorescence with synchrotron radiation, *Jones, Gordon, Hanson, Kwiatek and Pounds* 24 (1988) 313
Unbiased method for signal estimation in electron energy loss spectroscopy, concentrations measurements and detection limits in quantitative microanalysis: methods and programs, *Trebbia* 24 (1988) 399
Measurement of strain in silver halide particles by convergent-beam electron diffraction, *Vincent, Preston and King* 24 (1988) 409

Cryomicroscopy
Quantitative X-ray mapping of biological cryosections, *Fiori, Leapman, Swyt and Andrews* 24 (1988) 237

Diffraction and optical diffraction
Atomic site and species determinations using channeling and related effects in analytical electron microscopy, *Krishnan* 24 (1988) 125
Microdiffraction's contribution to microcharacterization, *Eades* 24 (1988) 143
Structure and microstructure in $Ba_2YCu_3O_{7-x}$, *Moodie and Whitfield* 24 (1988) 329
Electron diffraction studies of strain in epitaxial bicrystals and multilayers, *Cherns, Kiely and Preston* 24 (1988) 355
Dynamical investigations of electron channeling processes in a stepped crystal surface in reflection electron microscopy, *Wang* 24 (1988) 371
Measurement of strain in silver halide particles by convergent-beam electron diffraction, *Vincent, Preston and King* 24 (1988) 409

Electron energy-loss spectroscopy
High spatial resolution spectroscopy in the elemental microanalysis and imaging of biological systems, *Johnson, Izutsu, Cantino and Wong* 24 (1988) 221
Quantitative electron energy loss spectroscopy in biology, *Leapman and Ornberg* 24 (1988) 251
Operation modes of electron spectroscopic imaging and electron energy-loss spectroscopy in a transmission electron microscope, *Reimer, Fromm and Rennekamp* 24 (1988) 339
Unbiased method for signal estimation in electron energy loss spectroscopy, concentrations measurements and detection limits in quantitative microanalysis: methods and programs, *Trebbia* 24 (1988) 399

Electron probe microanalysis
Field electron emission, the atom probe and scanning tunneling spectroscopy, *Hren and Shedd* 24 (1988) 169
Capabilities and limitations of probe methods for the microanalysis of chemical elements in biology: a brief introduction, *Hall* 24 (1988) 181
Frontiers in electron probe microanalysis: applications to cell physiology, *LeFurgey, Bond and Ingram* 24 (1988) 185
High spatial resolution spectroscopy in the elemental microanalysis and imaging of biological systems, *Johnson, Izutsu, Cantino and Wong* 24 (1988) 221
Quantitative X-ray mapping of biological cryosections, *Fiori, Leapman, Swyt and Andrews* 24 (1988) 237
Proton microscopy and microanalysis – biological applications, *Legge, O'Brien, Kirby and Allan* 24 (1988) 283
Unbiased method for signal estimation in electron energy loss spectroscopy, concentrations measurements and detection limits in quantitative microanalysis: methods and programs, *Trebbia* 24 (1988) 399

High resolution
Lower limit of detectability at high spatial resolution of As implanted into Si using the JEOL 200CX in the STM-EDX mode, *Renteln and Ast* 24 (1988) 37
Assessing the information content of HREM images, *Fan and Cowley* 24 (1988) 49
Aspects of high resolution imaging with a scanning ion microprobe, *Levi-Setti, Chabala and Wang* 24 (1988) 97
Spectroscopic information from high resolution images, *Gronsky* 24 (1988) 155

High voltage
Spectroscopic information from high resolution images, *Gronsky* 24 (1988) 155

Image processing, 3D reconstruction
Guest editorial, *Eades* 24 (1988) v
Digital image processing of nanometer-size metal particles on amorphous substrates, *Soria, Artal, Bescos and Heinemann* 24 (1988) 19
Concerning "Angular reconstitution: a posteriori assignment of projection directions for 3D reconstruction", *Vainshtein, Goncharov, Ryskin and Vagin* 24 (1988) 61
Assessing the information content of HREM images, *Fan and Cowley* 24 (1988) 49
Addendum to "Angular reconstitution: a posteriori assignment of projection directions of 3D reconstruction", *Van Heel* 24 (1988) 62

Imaging
Observations of restricted beam-induced specimen motion with small-spot illumination, *Downing* 24 (1988) 387

Methods and techniques
A method for monitoring the collapse of plastic sections as a function of electron dose, *Luther, Lawrence and Crowther* 24 (1988) 7
Reducing focused ion beam charging effects on insulators by heating; a practical method for TEM specimen preparation of nonconductors, *Lundquist, Alani and Swann* 24 (1988) 27
Scanning electron beam submicron analytical techniques, *Buonaquisti and Russell* 24 (1988) 87
Sputter redeposition as a limit to spatially three-dimensional SIMS microanalysis, *Rüdenauer and Steiger* 24 (1988) 115
Microdiffraction's contribution to microcharacterization, *Eades* 24 (1988) 143
Capabilities and limitations of probe methods for the microanalysis of chemical elements in biology: a brief introduction, *Hall* 24 (1988) 181
Biological microanalysis by secondary ion mass spectrometry: status and prospects, *Burns* 24 (1988) 269
Photoelectron imaging and photoelectron labeling, *Griffith and Rempfer* 24 (1988) 299
X-ray fluorescence with synchrotron radiation, *Jones, Gordon, Hanson, Kwiatek and Pounds* 24 (1988) 313
Operation modes of electron spectroscopic imaging and electron energy-loss spectroscopy in a transmission electron microscope, *Reimer, Fromm and Rennekamp* 24 (1988) 339
Observations of restricted beam-induced specimen motion with small-spot illumination, *Downing* 24 (1988) 387
Unbiased method for signal estimation in electron energy loss spectroscopy, concentrations measurements and detection limits in quantitative microanalysis: methods and programs, *Trebbia* 24 (1988) 399

New developments
Guest editorial, *Eades* 24 (1988) v
Highly temperature-stable Si_3N_4 perforated grids, *Zandbergen, Pruymboom and Van Tendeloo* 24 (1988) 45
Field electron emission, the atom probe and scanning tunneling spectroscopy, *Hren and Shedd* 24 (1988) 169
Proton microscopy and microanalysis – biological applications, *Legge, O'Brien, Kirby and Allan* 24 (1988) 283
Photoelectron imaging and photoelectron labeling, *Griffith and Rempfer* 24 (1988) 299

Structure and microstructure in $Ba_2YCu_3O_{7-x}$, *Moodie and Whitfield* 24 (1988) 329

Particle optics, experimental
Realistic comparison of gun lens designs, *Barth* 24 (1988) 1

Particle optics, theory
Realistic comparison of gun lens designs, *Barth* 24 (1988) 1

Radiation damage and contamination
A method for monitoring the collapse of plastic sections as a function of electron dose, *Luther, Lawrence and Crowther* 24 (1988) 7

Reflection electron microscopy
Dynamical investigations of electron channeling processes in a stepped crystal surface in reflection electron microscopy, *Wang* 24 (1988) 371

Scanning transmission electron microscopy
Lower limit of detectability at high spatial resolution of As implanted into Si using the JEOL 200 CX in the STEM–EDX mode, *Renteln and Ast* 24 (1988) 37

Specimen preparation
Highly temperature-stable Si_3N_4 perforated grids, *Zandbergen, Pruymboom and Van Tendeloo* 24 (1988) 45

Surfaces, clusters, interfaces and particles
Digital image processing of nanometer-size metal particles on amorphous substrates, *Soria, Artal, Bescos and Heinemann* 24 (1988) 19
Electron diffraction studies of strain in epitaxial bicrystals and multilayers, *Cherns, Kiely and Preston* 24 (1988) 355
Dynamical investigations of electron channeling processes in a stepped crystal surface in reflection electron microscopy, *Wang* 24 (1988) 371
Measurement of strain in silver halide particles by convergent-beam electron diffraction, *Vincent, Preston and King* 24 (1988) 409

Abstracts / Announcements / Book reviews / Comments / Editorials / Reports / Miscellaneous
Guest editorial, *Eades* 24 (1988) v
Special announcement 24 (1988) 63
Selected abstracts of papers presented at the 40th Annual Meeting of the Scandinavian Society for Electron Microscopy SCANDEM-87, Bergen, June 1987 24 (1988) 65
Frontiers of submicron spectroscopy and biological microanalysis, a special biological symposium honoring T.A. Hall, Foreword, *Hren and Ingram, editors* 24 (1988) 83
Abstracts of papers presented at the Annual Conference of The Netherlands Society of Electron Microscopy, December 1987, *Woldringh, editor* 24 (1988) 421